

03500.119235.

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)	
TOSHIHIKO OUCHI	:	Examiner: S. Lee
)	
Application No.: 10/566,238	:	Group Art Unit: 2884
)	
Filed: January 30, 2006	:	
)	
For: SENSING APPARATUS	:	
)	Date: September 22, 2006

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. §1.56 and in accordance with the practice under 37 C.F.R. §§1.97 and 1.98, the Examiner's attention is directed to the documents listed below and on the enclosed Form PTO-1449.

- (1) JP 2003-509692 A
- (2) U.S. Patent Publication No. 2002/0137032
- (3) JP 2002-502028 A
- (4) U.S. Patent Publication No. 2001/0034030
- (5) WO 99/39190 A1
- (6) JP 5-188013 A
- (7) EP 0 519 250 A2
- (8) JP 2004-500546 A
- (9) U.S. Patent No. 6,828,558

- (10) O. Mitrofanov, et al., Terahertz near-field microscopy based on a collection mode detector, Appl. Phys. Lett. Vol. 77, No. 22, 2000, p. 3496-3498.
- (11) Hou-Tong Chen, et al., Terahertz imaging with nanometer resolution, Appl. Phys. Lett. Vol. 83, No. 15, 2003, p. 3009-3011.
- (12) U. Schade, et al., THz near-field imaging employing synchrotron radiation, Appl. Phys. Lett. Vol. 84, No. 8, 2004.02.23, p. 1422-1424.
- (13) O. Mitrofanov, et al., Study of single-cycle pulse propagation inside a terahertz near-field probe, Appl. Phys. Lett. Vol. 78, No. 2, 2001, p. 252-254.
- (14) Tatsuo Nozokido, et al., Scanning Near-Field Millimeter-Wave Microscope, Laser Kenkyu, Vol. 26, No. 7, 1998, p. 546-550.
- (15) Torsten Pfeifer, et al., Electro-Optic Near-Field Mapping of Planar Resonators, IEEE TRANSACTION ON ANTENNAS AND PROPAGATION, VOL. 46, NO. 2, 1998, p. 284-291.
- (16) S. Hunsche, et al., Near-field time-resolved imaging with far-infrared dipole sources, Conference on Lasers and Electro-Optics '98 TECHNICAL DIGEST, 1998, p. 64-65.
- (17) Masahiko Tani, et al., Application of THz radiation to imaging - Research and development in Japan, US and Europe, 2002 Nen Densi Jyoho Tsushin Gakkai Sogo Taikai Koen Ronbunshu Electronics 1, 2002, p. 491-492.

The foregoing documents were cited during prosecution of the PCT application corresponding to the above U.S. application. Copies of the International Search Report dated November 29, 2005, and the Written Opinion Of The International Searching Authority dated November 29, 2005, were filed in the present application on January 30, 2006.

Document (2) is believed to be an English-language counterpart of document (1); documents (4) and (5) are believed to be English-language counterparts of document (3); document (7) is believed to be an English-language counterpart of document (6); and document (9) is believed to be an English-language counterpart of document (8). English-language abstracts are provided for documents (6) and (14). Concise explanations

of relevance are believed to be provided by the English-language counterparts, the English-language abstracts, and/or the Written Opinion.

Inasmuch as this application has not yet received a first Office Action on the merits, it is believed that this Information Disclosure Statement is timely. See 37 C.F.R. § 1.97(b)(3). Accordingly, the Examiner is urged to study this information in its entirety and to form an independent determination of the materiality of the information to the claimed invention. Additionally, the Examiner is requested to indicate that this information has been considered by initialing the appropriate portion of the Form PTO-1449.

Applicant's undersigned attorney may be reached in our Costa Mesa, California office at (714) 540-8700. All correspondence should continue to be directed to our below-listed address.

Respectfully submitted,

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.119235		APPLICATION NO. 10,566,238	
				APPLICANT TOSHIHIKO OUCHI			
				FILING DATE January 30, 2006		GROUP 2884	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0137032	09/26/2002	Hefti	435	6	
		2001/0034030	10/25/2001	Hefti	435	6	
		6,828,558	12/07/2004	Arnone	250	341.1	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		2003-509692 A	03/22/2003	JAPAN			No
		2002-502028 A	01/22/2002	JAPAN			No
		WO 99/39190	08/05/1999	PCT			No
		5-188013 A	07/27/1993	Japan			Abstract
		0 519 250	12/23/1992	Europe			No
		2004-500546 A	01/08/2004	Japan			No

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	O. Mitrofanov, et al., Terahertz near-field microscopy based on a collection mode detector, Appl. Phys. Lett. Vol. 77, No. 22, 2000, p. 3496-3498.
	Hou-Tong Chen, et al., Terahertz imaging with nanometer resolution, Appl. Phys. Lett. Vol. 83, No. 15, 2003, p. 3009-3011.
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	O. Mitrofanov, et al., Study of single-cycle pulse propagation inside a terahertz near-field probe, Appl. Phys. Lett. Vol. 78, No. 2, 2001, p. 252-254.
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	S. Hunsche, et al., Near-field time-resolved imaging with far-infrared dipole sources, Conference on Lasers and Electro-Optics '98 TECHNICAL DIGEST, 1998, p. 64-65.
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EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1